

**INFORMATION DISCLOSURE CITATION**  
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15715 U.S. PTO  
10/02/04  
12/21/01

Atty. Docket No.	08048.0022-00000	Application No.	Unassigned
Applicant	Roland BAZIN		
Filing Date	December 21, 2001	Group:	Unassigned

**U.S. PATENT DOCUMENTS**

Examiner Initial*		Document Number	Date	Name	Class	Sub Class	Filing Date If Appropriate
AW	1	4,276,570 A	Jun. 30, 1981	Burson et al.	358	903	
AW	2	4,670,781 A	Jun. 2, 1987	Aubert et al.	358	93	
AW	3	5,016,173 A	May 14, 1991	Kenet et al.	364	413.13	
AW	4	5,796,862 A	Aug. 18, 1998	Pawlicki et al.	382	132	
AW	5	5,836,872 A	Nov. 17, 1998	Kenet et al.	600	306	

**FOREIGN PATENT DOCUMENTS**

		Document Number	Date	Country	Class	Sub Class	Translation Yes or No
AW	6	DE 196 22 569 A1	Dec. 11, 1997	Germany	G01B	11/30	Abstract
AW	7	FR 2 565 481 A1	Dec. 13, 1985	France	A61B	5/10	No
AW	8	GB 2 288 511 A	Oct. 18, 1995	Great Britain	H04N	7/18	N/A
AW	9	JP 5-253210 A	Oct. 5, 1993	Japan	A61B	5/107	Abstract
AW	10	WO 97/47235 A1	Dec. 18, 1997	PCT	A61B	5/00	N/A
AW	11	WO 98/37811 A1	Sep. 3, 1998	PCT	A61B	6/08	N/A
AW	12	WO 00/76398 A1	Dec. 21, 2000	PCT	A61B	5/103	N/A

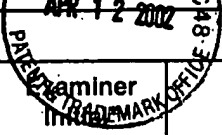
**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

AW	13	English language Derwent Abstract of DE 196 22 569, Dec. 11, 1997.
AW	14	English language Derwent Abstract of JP 5-253210, Oct. 5, 1993.

Examiner	AW	ANDREW W. JOHNS PRIMARY EXAMINER	Date Considered	22 Feb 2005
<p>*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>				
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**INFORMATION DISCLOSURE CITATION**  
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Atty. Docket No. 08048.0022-00000	Application No. 10/024,034
Applicant Roland BAZIN	
Filing Date December 21, 2001	Group: 2621

U.S. PATENT DOCUMENTS							
Examiner	Document Number	Date	Name	Class	Sub Class	Filing Date If Appropriate	
							
			Technology Center 2600				

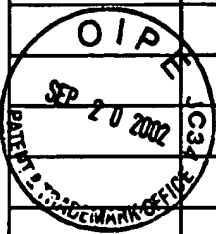
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Sub Class	Translation Yes or No	
AAT	WO 98/21695 A1	May 22, 1998	PCT	G06T	17/40	N/A	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		

Examiner <i>AAT</i> ANDREW W. JOHNS PRIMARY EXAMINER	Date Considered 22 Feb 2005
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Atty. Docket No.	08048.0022-00000	Application No.	10/024,034
Applicant	Roland BAZIN		
Filing Date	December 21, 2001	Group:	2621

U.S. PATENT DOCUMENTS							
Examiner Initial*		Document Number	Date	Name	Class	Sub Class	Filing Date If Appropriate
							
				RECEIVED			
				SEP 24 2002			
				Technology Center 2600			
							RECEIVED
							SEP 24 2002
							Technology Center 2100

FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Sub Class	Translation Yes or No
<i>AAJ</i>	1	EP 1 030 267 A1	Aug. 23, 2000	Europe	G06T	1/00	N/A
<i>AAJ</i>	2	EP 1 134 701 A2	Sep. 19, 2001	Europe	G06T	17/00	N/A
<i>AAJ</i>	3	WO 98/20458 A1	May 14, 1998	PCT	G06T	11/20	N/A
<i>AAJ</i>	4	WO 00/43956 A2	Jul. 27, 2000	PCT	G06T	15/70	N/A
<i>AAJ</i>	5	WO 01/46906 A2	Jun. 28, 2001	PCT	G06T	15/70	N/A

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
<i>AAJ</i>	6	A.A. Bukharaev et al., "AFM investigation of selective etching mechanism of nanostructured silica," 19 <sup>th</sup> European Conference on Surface Science, Madrid, Spain, Vol. 485, pt. 2, Sept. 5-8, 2000, pp. 1319-1324.

Examiner	<i>AAJ</i> ANDREW W. JOHNS PRIMARY EXAMINER	Date Considered	22 Feb 2005
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